

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10582000	INOUE ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Heincer, Liam J	1709

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
525	237	9/10/07	LH

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST Search (USPAT, USPGPub, USOCR, EPO, JPO, DERWENT) see search report	9/10/07	LH
Inventor Name Search	9/10/07	LH
PLUS Search	9/6/07	LH
Updated EAST Search (USPAT, USPGPub, USOCR, EPO, JPO, DERWENT) see search report	2/28/08	LH
Updated EAST Search (USPAT, USPGPub, USOCR, EPO, JPO, DERWENT) see search report	10/9/08	LH
Updated EAST Search (USPAT, USPGPub, USOCR, EPO, JPO, DERWENT) see search report	4/27/09	LH
Updated EAST Search (USPAT, USPGPub, USOCR, EPO, JPO, DERWENT) see search report	12/23/2009	LH
Updated EAST Search (USPAT, USPGPub, USOCR, EPO, JPO, DERWENT) see search report	6/16/2010	LH
Updated EAST Search (USPAT, USPGPub, USOCR, EPO, JPO, DERWENT) see search report	12/3/2010	LH
Updated EAST Search (USPAT, USPGPub, USOCR, EPO, JPO, DERWENT) see search report	7/25/2011	LH
Updated EAST Search (USPAT, USPGPub, USOCR, EPO, JPO, DERWENT) see search report	12/20/2011	LH

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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